

Notice of References Cited	Application/Control No. 09/871,527		Applicant(s)/Patent Under Reexamination VON DREELE ET AL.	
	Examiner Carolyn L Smith		Art Unit 1631	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,667,299 B1	12-2003	Ahlem et al.	514/178
	C	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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	U	Heiney. "What is X-ray diffraction (XRD)", 1996, on the world wide web at http://dept.physics.upenn.edu/~heiney/talks/hires/whatis.html#SECTION00014000000000000000 , 4 pages.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.